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LOW SKEW, 1-TO-24 DIFFERENTIAL-TO-LVCMOS/LVTTL FANOUT BUFFER

ICS8344-01

GENERAL DESCRIPTION

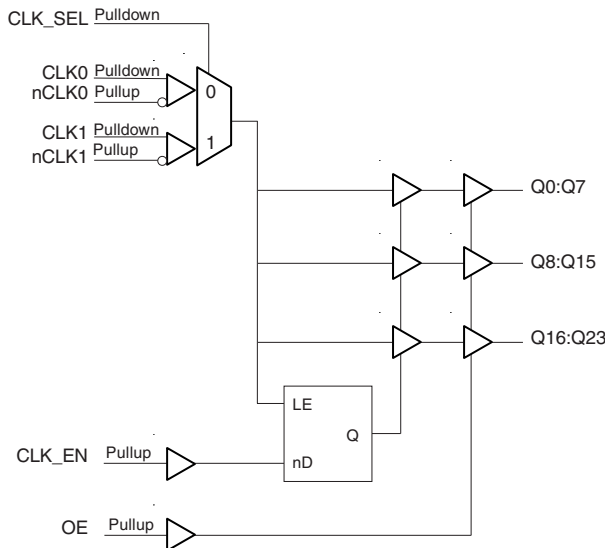
 The ICS8344-01 is a low voltage, low skew fanout buffer and a member of the HiPerClockS™ family of High Performance Clock Solutions from IDT. The ICS8344-01 has two selectable clock inputs. The CLKx, nCLKx pairs can accept most standard differential input levels. The ICS8344-01 is designed to translate any differential signal level to LVCMOS/LVTTL levels. The low impedance LVCMOS/LVTTL outputs are designed to drive 50Ω series or parallel terminated transmission lines. The effective fanout can be increased to 48 by utilizing the ability of the outputs to drive two series terminated lines. Redundant clock applications can make use of the dual clock inputs which also facilitate board level testing. The clock enable is internally synchronized to eliminate runt pulses on the outputs during asynchronous assertion/deassertion of the clock enable pin. The outputs are driven low when disabled. The ICS8344-01 is characterized at full 3.3V, full 2.5V and mixed 3.3V input and 2.5V output operating supply modes.

Guaranteed output and part-to-part skew characteristics make the ICS8344-01 ideal for those clock distribution applications demanding well defined performance and repeatability.

FEATURES

- Twenty-four LVCMOS/LVTTL outputs, 7Ω typical output impedance
- Two selectable differential CLKx, nCLKx inputs
- CLK0, nCLK0 and CLK1, nCLK1 pairs can accept the following input levels: LVDS, LVPECL, LVHSTL, SSTL, HCSL
- Output frequency up to 250MHz
- Translates any single ended input signal to LVCMOS/LVTTL with resistor bias on nCLK input
- Synchronous clock enable
- Additive phase jitter RMS: 0.21ps (typical)
- Output skew: 200ps (maximum)
- Part-to-part skew: 900ps (maximum)
- Bank skew: 85ps (maximum)
- Propagation delay: 5ns (maximum)
- Output supply modes:
Core/Output
3.3V/3.3V
2.5V/2.5V
3.3V/2.5V
- 0°C to 70°C ambient operating temperature
- Available in both standard (RoHS 5) and lead-free (RoHS 6) packages

BLOCK DIAGRAM



PIN ASSIGNMENT

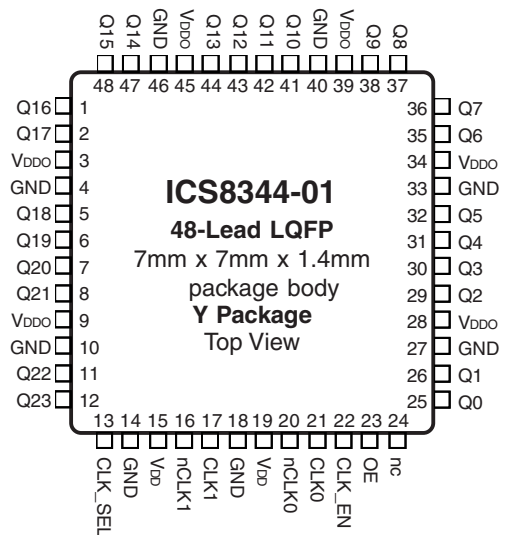


TABLE 1. PIN DESCRIPTIONS

Number	Name	Type		Description
1, 2, 5, 6 7, 8, 11, 12	Q16, Q17, Q18, Q19 Q20, Q21, Q22, Q23	Output		Q16 thru Q23 outputs. 7Ω typical output impedance.
3, 9, 28, 34, 39, 45	V _{DDO}	Power		Output supply pins. Connect 3.3V or 2.5V.
4, 10, 14,18, 27, 33, 40, 46	GND	Power		Power supply ground. Connect to ground.
13	CLK_SEL	Input	Pulldown	Clock select input. When HIGH, selects CLK1, nCLK inputs, When LOW, selects CLK0, nCLK0 inputs. LVCMOS / LVTTTL interface levels.
15, 19	V _{DD}	Power		Positive supply pins. Connect 3.3V or 2.5V.
16	nCLK1	Input	Pullup	Inverting differential LVPECL clock input.
17	CLK1	Input	Pulldown	Non-inverting differential LVPECL clock input.
20	nCLK0	Input	Pullup	Inverting differential LVPECL clock input.
21	CLK0	Input	Pulldown	Non-inverting differential LVPECL clock input.
22	CLK_EN	Input	Pullup	Synchronizing control for enabling and disabling clock outputs. LVCMOS interface levels.
23	OE	Input	Pullup	Output enable. Controls enabling and disabling of outputs Q0 thru Q23.
24	nc	Unused		No connect.
25, 26, 29, 30 31, 32, 35, 36	Q0, Q1, Q2, Q3 Q4, Q5, Q6, Q7	Output		Q0 thru Q7 outputs. 7Ω typical output impedance.
37, 38, 41, 42 43, 44, 47, 48	Q8, Q9, Q10, Q11 Q12, Q13, Q14, Q15	Output		Q8 thru Q15 outputs. 7Ω typical output impedance.

NOTE: *Pullup* and *Pulldown* refer to internal input resistors. See Table 2, Pin Characteristics, for typical values.

TABLE 2. PIN CHARACTERISTICS

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
C _{IN}	Input Capacitance	CLK0, nCLK0, CLK1, nCLK1			4	pF
		CLK_SEL, CLK_EN, OE			4	pF
C _{PD}	Power Dissipation Capacitance (per output)	V _{DDO} = 3.465V		23		pF
		V _{DDO} = 2.675V		16		pF
R _{PULLUP}	Input Pullup Resistor			51		kΩ
R _{PULLDOWN}	Input Pulldown Resistor			51		kΩ
R _{OUT}	Output Impedance			7		Ω

TABLE 3A. OUTPUT ENABLE FUNCTION TABLE

Banks 1, 2, 3		
Inputs		Outputs
OE	CLK_EN	Q0-Q23
0	X	Hi-Z
1	0	Disabled in logic LOW state. NOTE 1
1 (default)	1 (default)	Enabled. NOTE 1

NOTE 1: The clock enable and disable function is synchronous to the falling edge of the selected reference clock.

TABLE 3B. CLOCK SELECT FUNCTION TABLE

Control Input	Clock	
CLK_SEL	CLK0, nCLK0	CLK1, nCLK1
0 (default)	Selected	De-selected
1	De-selected	Selected

TABLE 3C. CLOCK INPUT FUNCTION TABLE

Inputs			Outputs	Input to Output Mode	Polarity
OE	CLK0, CLK1	nCLK0, nCLK1	Q0 thru Q23		
1 (default)	0 (default)	1 (default)	LOW	Differential to Single Ended	Non Inverting
1	1	0	HIGH	Differential to Single Ended	Non Inverting
1	0	Biased; NOTE 1	LOW	Single Ended to Differential	Non Inverting
1	1	Biased; NOTE 1	HIGH	Single Ended to Differential	Non Inverting
1	Biased; NOTE 1	0	HIGH	Single Ended to Differential	Inverting
1	Biased; NOTE 1	1	LOW	Single Ended to Differential	Inverting

NOTE 1: Please refer to the Application Information section on page 8, Figure 1, which discusses *Wiring the Differential Input to Accept Single-Ended Levels*.

ABSOLUTE MAXIMUM RATINGS

Supply Voltage, V_{DD}	4.6V
Inputs, V_I	-0.5V to $V_{DD} + 0.5$ V
Outputs, V_O	-0.5V to $V_{DDO} + 0.5$ V
Package Thermal Impedance, θ_{JA}	47.9°C/W (0 lfpm)
Storage Temperature, T_{STG}	-65°C to 150°C

NOTE: Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of product at these conditions or any conditions beyond those listed in the *DC Characteristics* or *AC Characteristics* is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability.

TABLE 4A. POWER SUPPLY DC CHARACTERISTICS, $V_{DD} = V_{DDO} = 3.3V \pm 5\%$, $T_A = 0^\circ\text{C}$ TO 70°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V_{DD}	Positive Supply Voltage		3.135	3.3	3.465	V
V_{DDO}	Output Supply Voltage		3.135	3.3	3.465	V
I_{DD}	Quiescent Power Supply Current				95	mA

TABLE 4B. POWER SUPPLY DC CHARACTERISTICS, $V_{DD} = 3.3V \pm 5\%$, $V_{DDO} = 2.5V \pm 5\%$, $T_A = 0^\circ\text{C}$ TO 70°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V_{DD}	Positive Supply Voltage		3.135	3.3	3.465	V
V_{DDO}	Output Supply Voltage		2.375	2.5	2.625	V
I_{DD}	Quiescent Power Supply Current				95	mA

TABLE 4C. POWER SUPPLY DC CHARACTERISTICS, $V_{DD} = V_{DDO} = 2.5V \pm 5\%$, $T_A = 0^\circ\text{C}$ TO 70°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V_{DD}	Positive Supply Voltage		2.375	2.5	2.625	V
V_{DDO}	Output Supply Voltage		2.375	2.5	2.625	V
I_{DD}	Quiescent Power Supply Current				95	mA

TABLE 4D. LVCMOS/LVTTL DC CHARACTERISTICS, $V_{DD} = V_{DDO} = 3.3V \pm 5\%$, $T_A = 0^\circ\text{C}$ TO 70°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V_{IH}	Input High Voltage	CLK_SEL, CLK_EN, OE	2		3.8	V
V_{IL}	Input Low Voltage	CLK_SEL, CLK_EN, OE	-0.3		0.8	V
I_{IH}	Input High Current	CLK_EN, OE	$V_{DD} = V_{IN} = 3.465$ V		5	μ A
		CLK_SEL	$V_{DD} = V_{IN} = 3.465$ V		150	μ A
I_{IL}	Input Low Current	CLK_EN, OE	$V_{DD} = 3.465$, $V_{IN} = 0$ V	-150		μ A
		CLK_SEL	$V_{DD} = 3.465$, $V_{IN} = 0$ V	-5		μ A
V_{OH}	Output High Voltage	$V_{DD} = V_{DDO} = 3.135$ V $I_{OH} = -36$ mA	2.7			V
V_{OL}	Output Low Voltage	$V_{DD} = V_{DDO} = 3.135$ V $I_{OL} = 36$ mA			0.5	V

TABLE 4E. LVCMOS/LVTTL DC CHARACTERISTICS, $V_{DD} = 3.3V \pm 5\%$, $V_{DDO} = 2.5V \pm 5\%$, $T_A = 0^\circ C$ TO $70^\circ C$

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V_{IH}	Input High Voltage	CLK_SEL, CLK_EN, OE	2		3.8	V
V_{IL}	Input Low Voltage	CLK_SEL, CLK_EN, OE	-0.3		0.8	V
I_{IH}	Input High Current	CLK_EN, OE	$V_{DD} = V_{IN} = 3.465V$		5	μA
		CLK_SEL	$V_{DD} = V_{IN} = 3.465V$		150	μA
I_{IL}	Input Low Current	CLK_EN, OE	$V_{DD} = 3.465, V_{IN} = 0V$	-150		μA
		CLK_SEL	$V_{DD} = 3.465, V_{IN} = 0V$	-5		μA
V_{OH}	Output High Voltage		$V_{DD} = 3.135V$ $V_{DDO} = 2.375V$ $I_{OH} = -27mA$	1.9		V
V_{OL}	Output Low Voltage		$V_{DD} = 3.135V$ $V_{DDO} = 2.375V$ $I_{OL} = 27mA$		0.4	V

TABLE 4F. LVCMOS/LVTTL DC CHARACTERISTICS, $V_{DD} = V_{DDO} = 2.5V \pm 5\%$, $T_A = 0^\circ C$ TO $70^\circ C$

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V_{IH}	Input High Voltage	CLK_SEL, CLK_EN, OE	2		2.9	V
V_{IL}	Input Low Voltage	CLK_SEL, CLK_EN, OE	-0.3		0.8	V
I_{IH}	Input High Current	CLK_EN, OE	$V_{DD} = V_{IN} = 2.625V$		5	μA
		CLK_SEL	$V_{DD} = V_{IN} = 2.625V$		150	μA
I_{IL}	Input Low Current	CLK_EN, OE	$V_{DD} = 2.625, V_{IN} = 0V$	-150		μA
		CLK_SEL	$V_{DD} = 2.625, V_{IN} = 0V$	-5		μA
V_{OH}	Output High Voltage		$V_{DD} = V_{DDO} = 2.375V$ $I_{OH} = -27mA$	1.9		V
V_{OL}	Output Low Voltage		$V_{DD} = V_{DDO} = 2.375V$ $I_{OL} = 27mA$		0.4	V

TABLE 4G. DIFFERENTIAL DC CHARACTERISTICS, $V_{DD} = V_{DDO} = 3.3V \pm 5\%$, $T_A = 0^\circ C$ TO $70^\circ C$

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
I_{IH}	Input High Current	nCLK0, nCLK1	$V_{DD} = V_{IN} = 3.465V$		5	μA
		CLK0, CLK1	$V_{DD} = V_{IN} = 3.465V$		150	μA
I_{IL}	Input Low Current	nCLK0, nCLK1	$V_{DD} = 3.465V, V_{IN} = 0V$	-150		μA
		CLK0, CLK1	$V_{DD} = 3.465V, V_{IN} = 0V$	-5		μA
V_{PP}	Peak-to-Peak Input Voltage		0.3		1.3	V
V_{CMR}	Common Mode Input Voltage: NOTE 1, 2		0.9		2	V

NOTE 1: For single ended applications, the maximum input voltage for CLK0, nCLK0 and CLK1, nCLK1 is $V_{DD} + 0.3V$.

NOTE 2: Common mode voltage is defined as V_{IH} .

TABLE 4H. DIFFERENTIAL DC CHARACTERISTICS, $V_{DD} = 3.3V \pm 5\%$, $V_{DDO} = 2.5V \pm 5\%$, $T_A = 0^\circ C$ TO $70^\circ C$

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
I_{IH}	Input High Current	nCLK0, nCLK1	$V_{DD} = V_{IN} = 3.465V$		5	μA
		CLK0, CLK1	$V_{DD} = V_{IN} = 3.465V$		150	μA
I_{IL}	Input Low Current	nCLK0, nCLK1	$V_{DD} = 3.465V,$ $V_{IN} = 0V$	-150		μA
		CLK0, CLK1	$V_{DD} = 3.465V,$ $V_{IN} = 0V$	-5		μA
V_{PP}	Peak-to-Peak Input Voltage		0.3		1.3	V
V_{CMR}	Common Mode Input Voltage; NOTE 1, 2		0.9		2	V

NOTE 1: For single ended applications, the maximum input voltage for CLK0, nCLK0 and CLK1, nCLK1 is $V_{DD} + 0.3V$.

NOTE 2: Common mode voltage is defined as V_{IH} .

TABLE 4I. DIFFERENTIAL DC CHARACTERISTICS, $V_{DD} = V_{DDO} = 2.5V \pm 5\%$, $T_A = 0^\circ C$ TO $70^\circ C$

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
I_{IH}	Input High Current	nCLK0, nCLK1	$V_{DD} = V_{IN} = 2.625V$		5	μA
		CLK0, CLK1	$V_{DD} = V_{IN} = 2.625V$		150	μA
I_{IL}	Input Low Current	nCLK0, nCLK1	$V_{DD} = 2.625V, V_{IN} = 0V$	-150		μA
		CLK0, CLK1	$V_{DD} = 2.625V, V_{IN} = 0V$	-5		μA
V_{PP}	Peak-to-Peak Input Voltage		0.3		1.3	V
V_{CMR}	Common Mode Input Voltage; NOTE 1, 2		0.9		2	V

NOTE 1: For single ended applications, the maximum input voltage for CLK0, nCLK0 and CLK1, nCLK1 is $V_{DD} + 0.3V$.

NOTE 2: Common mode voltage is defined as V_{IH} .

**TABLE 5. AC CHARACTERISTICS, $V_{DD} = V_{DDO} = 3.3V \pm 5\%$; $V_{DD} = 3.3V \pm 5\%$, $V_{DDO} = 2.5V \pm 5\%$;
 $V_{DD} = V_{DDO} = 2.5V \pm 5\%$, $T_A = 0^\circ\text{C TO } 70^\circ\text{C}$**

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
f_{MAX}	Maximum Output Frequency				250	MHz
t_{PD}	Propagation Delay, NOTE 1	$f \leq 200\text{MHz}$	2.5		5	ns
t_{jit}	Buffer Additive Phase Jitter, RMS; refer to Additive Phase Jitter Section	155.52MHz, Integration Range: 12kHz - 20MHz		0.21		ps
$t_{sk}(b)$	Bank Skew; NOTE 2, 6	Q[0:7]	Measured on the rising edge of $V_{DDO}/2$		85	ps
		Q[8:15]			180	ps
		Q[16:23]			100	ps
$t_{sk}(o)$	Output Skew; NOTE 3, 6	Measured on the rising edge of $V_{DDO}/2$			200	ps
$t_{sk}(pp)$	Part-to-Part Skew; NOTE 4, 6	Measured on the rising edge of $V_{DDO}/2$			900	ps
t_R	Output Rise Time; NOTE 5	30% to 70%	200		800	ps
t_F	Output Fall Time; NOTE 5	30% to 70%	200		800	ps
odc	Output Duty Cycle	$f \leq 200\text{MHz}$	$t_{CYCLE}/2 - 0.25$	$t_{CYCLE}/2$	$t_{CYCLE}/2 + 0.25$	%
		$f = 200\text{MHz}$	2.25	2.5	2.75	ns
t_{EN}	Output Enable Time; NOTE 5	$f = 10\text{MHz}$			5	ns
t_{DIS}	Output Disable Time; NOTE 5	$f = 10\text{MHz}$			4	ns

All parameters measured at 200MHz and V_{pp} typ unless noted otherwise.

NOTE 1: Measured from the differential input crossing point to $V_{DDO}/2$.

NOTE 2: Defined as skew within a bank of outputs at the same voltage and with equal load conditions.

NOTE 3: Defined as skew across banks of outputs at the same supply voltage and with equal load conditions.

NOTE 4: Defined as between outputs at the same supply voltage and with equal load conditions. Measured at $V_{DDO}/2$.

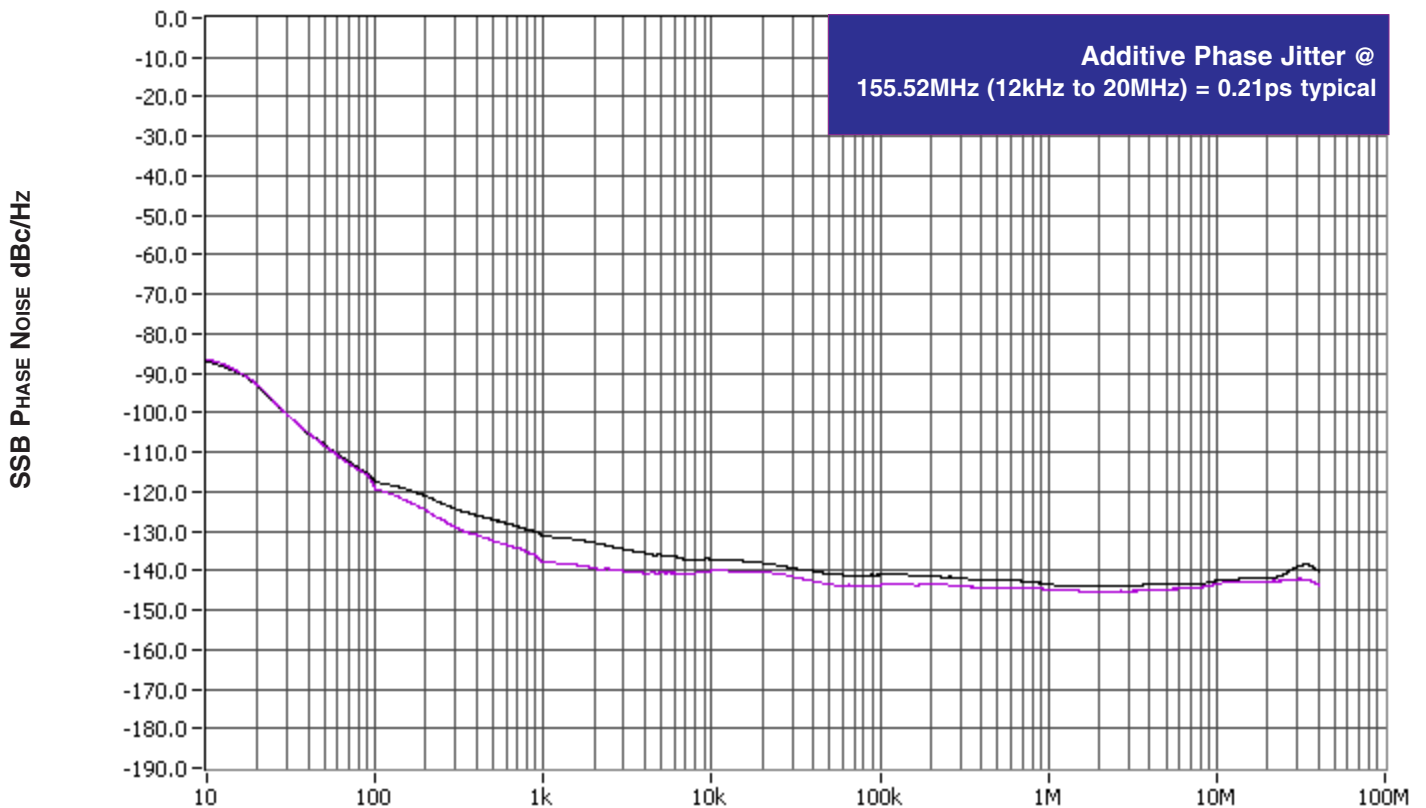
NOTE 5: These parameters are guaranteed by characterization. Not tested in production.

NOTE 6: This parameter is defined in accordance with JEDEC Standard 65.

ADDITIVE PHASE JITTER

The spectral purity in a band at a specific offset from the fundamental compared to the power of the fundamental is called the **dBc Phase Noise**. This value is normally expressed using a Phase noise plot and is most often the specified plot in many applications. Phase noise is defined as the ratio of the noise power present in a 1Hz band at a specified offset from the fundamental frequency to the power value of the fundamental. This ratio is expressed in decibels (dBm) or a ratio of the power in the 1Hz

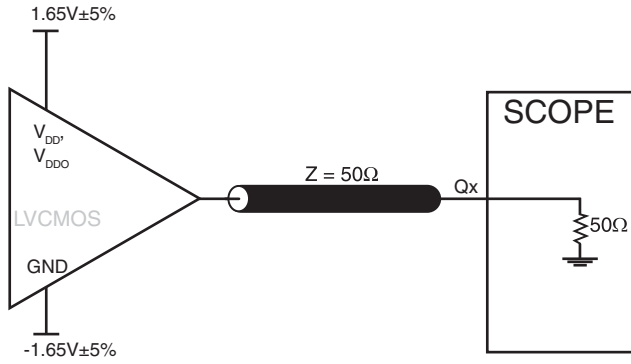
band to the power in the fundamental. When the required offset is specified, the phase noise is called a **dBc** value, which simply means dBm at a specified offset from the fundamental. By investigating jitter in the frequency domain, we get a better understanding of its effects on the desired application over the entire time record of the signal. It is mathematically possible to calculate an expected bit error rate given a phase noise plot.



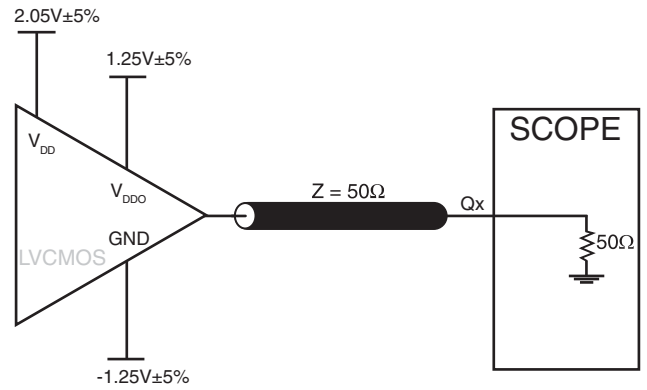
As with most timing specifications, phase noise measurements has issues relating to the limitations of the equipment. Often the noise floor of the equipment is higher than the noise floor of the

device. This is illustrated above. The device meets the noise floor of what is shown, but can actually be lower. The phase noise is dependent on the input source and measurement equipment.

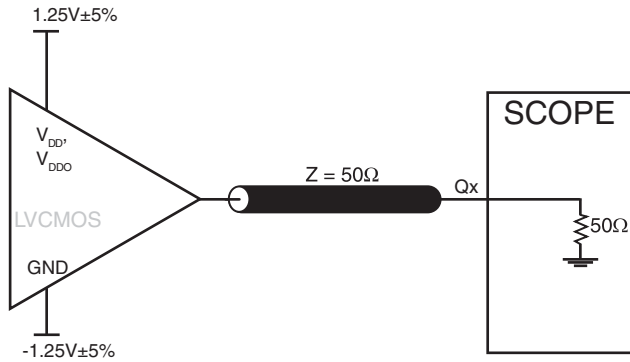
PARAMETER MEASUREMENT INFORMATION



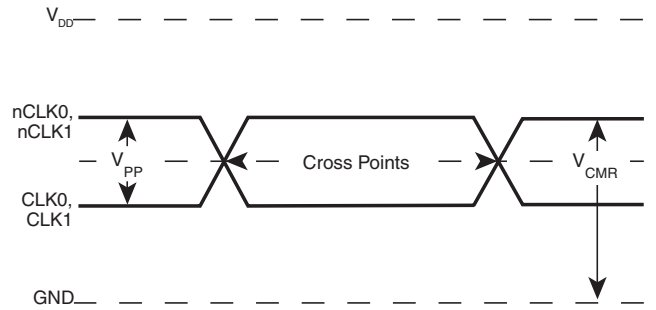
3.3V OUTPUT LOAD AC TEST CIRCUIT



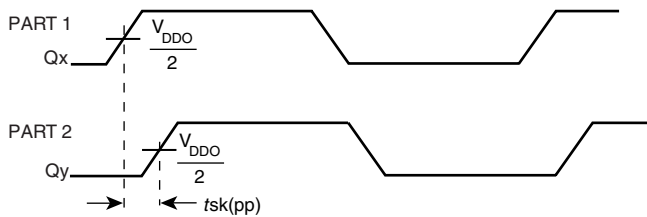
3.3V CORE/2.5V OUTPUT LOAD AC TEST CIRCUIT



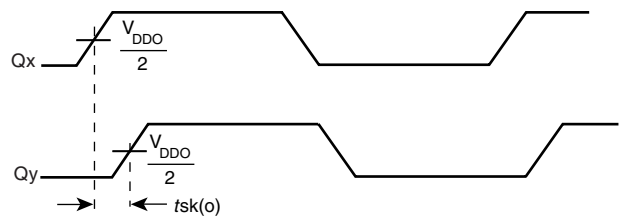
2.5V OUTPUT LOAD AC TEST CIRCUIT



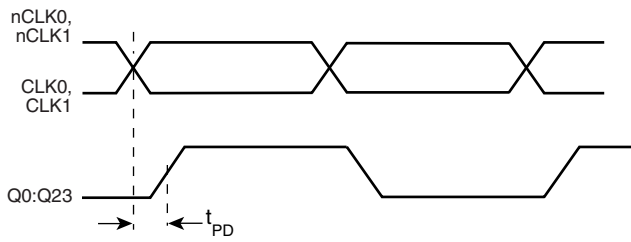
DIFFERENTIAL INPUT LEVEL



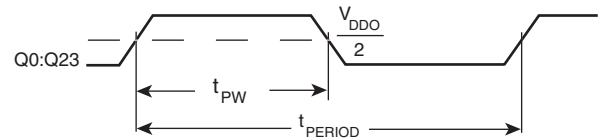
PART-TO-PART SKEW



OUTPUT SKEW

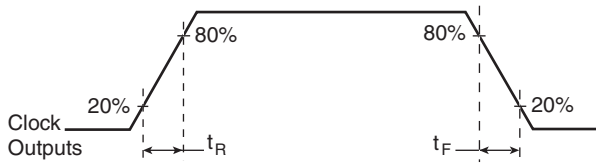


PROPAGATION DELAY



$$\text{odc} = \frac{t_{PW}}{t_{PERIOD}} \times 100\%$$

OUTPUT DUTY CYCLE/PULSE WIDTH/PERIOD



OUTPUT RISE/FALL TIME

APPLICATION INFORMATION

WIRING THE DIFFERENTIAL INPUT TO ACCEPT SINGLE ENDED LEVELS

Figure 1 shows how the differential input can be wired to accept single ended levels. The reference voltage $V_{REF} = V_{DD}/2$ is generated by the bias resistors R1, R2 and C1. This bias circuit should be located as close as possible to the input pin. The ratio

of R1 and R2 might need to be adjusted to position the V_{REF} in the center of the input voltage swing. For example, if the input clock swing is only 2.5V and $V_{DD} = 3.3V$, V_{REF} should be 1.25V and $R2/R1 = 0.609$.

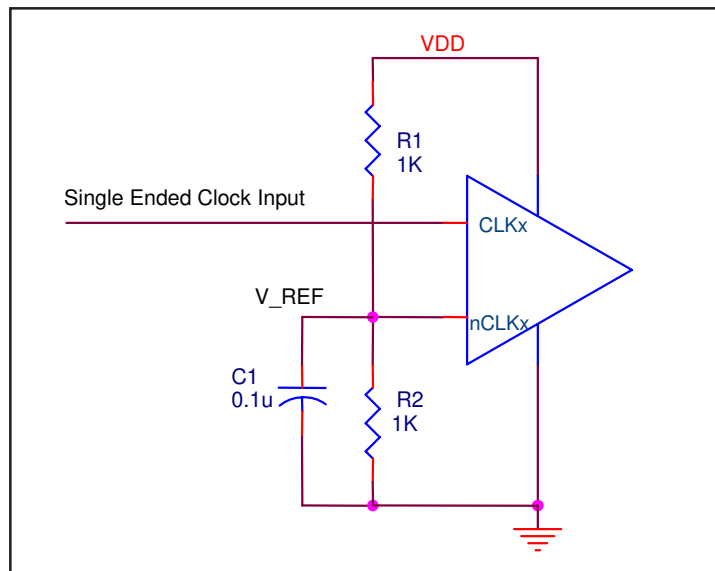


FIGURE 1. SINGLE ENDED SIGNAL DRIVING DIFFERENTIAL INPUT

RECOMMENDATIONS FOR UNUSED INPUT AND OUTPUT PINS

INPUTS:

CLK/nCLK INPUT:

For applications not requiring the use of the differential input, both CLK and nCLK can be left floating. Though not required, but for additional protection, a 1k Ω resistor can be tied from CLK to ground.

LVC MOS CONTROL PINS:

All control pins have internal pull-ups or pull-downs; additional resistance is not required but can be added for additional protection. A 1k Ω resistor can be used.

OUTPUTS:

LVC MOS OUTPUT:

All unused LVC MOS output can be left floating. There should be no trace attached.

DIFFERENTIAL CLOCK INPUT INTERFACE

The CLK /nCLK accepts LVDS, LVPECL, LVHSTL, SSTL, HCSL and other differential signals. Both V_{SWING} and V_{OH} must meet the V_{PP} and V_{CMR} input requirements. Figures 2A to 2E show interface examples for the HiPerClockS CLK/nCLK input driven by the most common driver types. The input interfaces suggested here are

examples only. Please consult with the vendor of the driver component to confirm the driver termination requirements. For example in *Figure 2A*, the input termination applies for IDT HiPerClockS LVHSTL drivers. If you are using an LVHSTL driver from another vendor, use their termination recommendation.

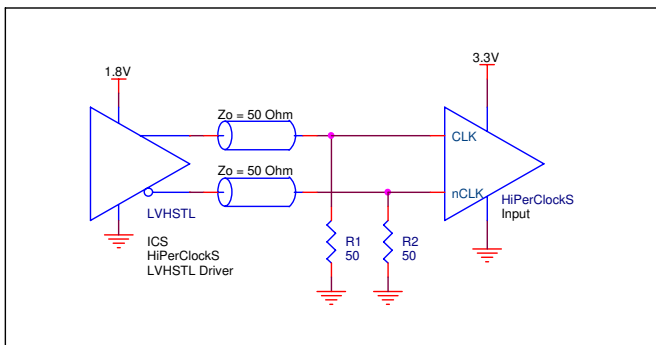


FIGURE 2A. HiPerClockS CLK/nCLK INPUT DRIVEN BY IDT HiPerClockS LVHSTL DRIVER

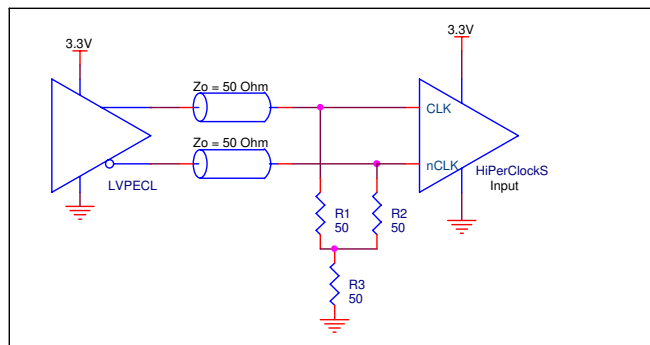


FIGURE 2B. HiPerClockS CLK/nCLK INPUT DRIVEN BY 3.3V LVPECL DRIVER

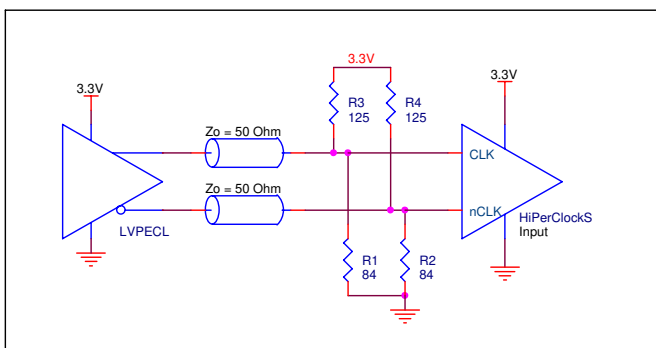


FIGURE 2C. HiPerClockS CLK/nCLK INPUT DRIVEN BY 3.3V LVPECL DRIVER

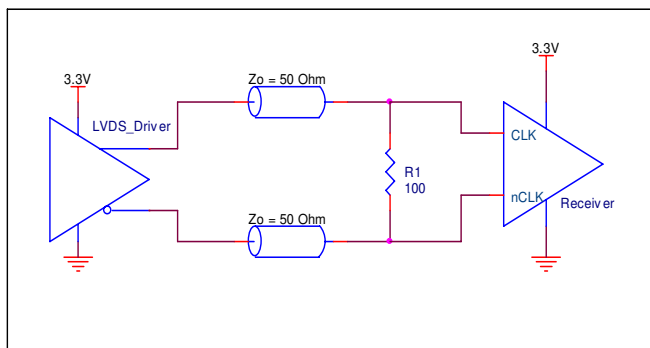


FIGURE 2D. HiPerClockS CLK/nCLK INPUT DRIVEN BY 3.3V LVDS DRIVER

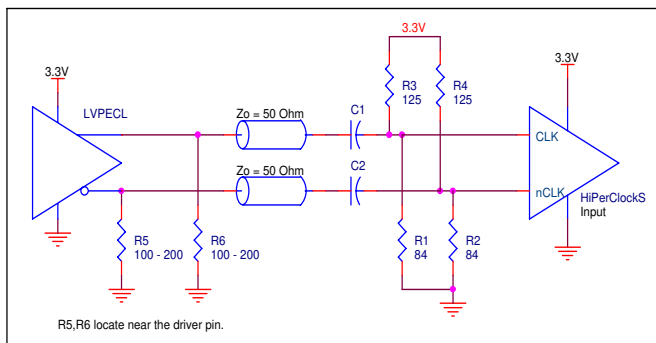


FIGURE 2E. HiPerClockS CLK/nCLK INPUT DRIVEN BY 3.3V LVPECL DRIVER WITH AC COUPLE

RELIABILITY INFORMATION

TABLE 6. θ_{JA} vs. AIR FLOW TABLE FOR 48 LEAD LQFP

	θ_{JA} by Velocity (Linear Feet per Minute)		
	0	200	500
Single-Layer PCB, JEDEC Standard Test Boards	67.8°C/W	55.9°C/W	50.1°C/W
Multi-Layer PCB, JEDEC Standard Test Boards	47.9°C/W	42.1°C/W	39.4°C/W

NOTE: Most modern PCB designs use multi-layered boards. The data in the second row pertains to most designs.

TRANSISTOR COUNT

The transistor count for ICS8344-01 is: 1503

PACKAGE OUTLINE - Y SUFFIX FOR 48 LEAD LQFP

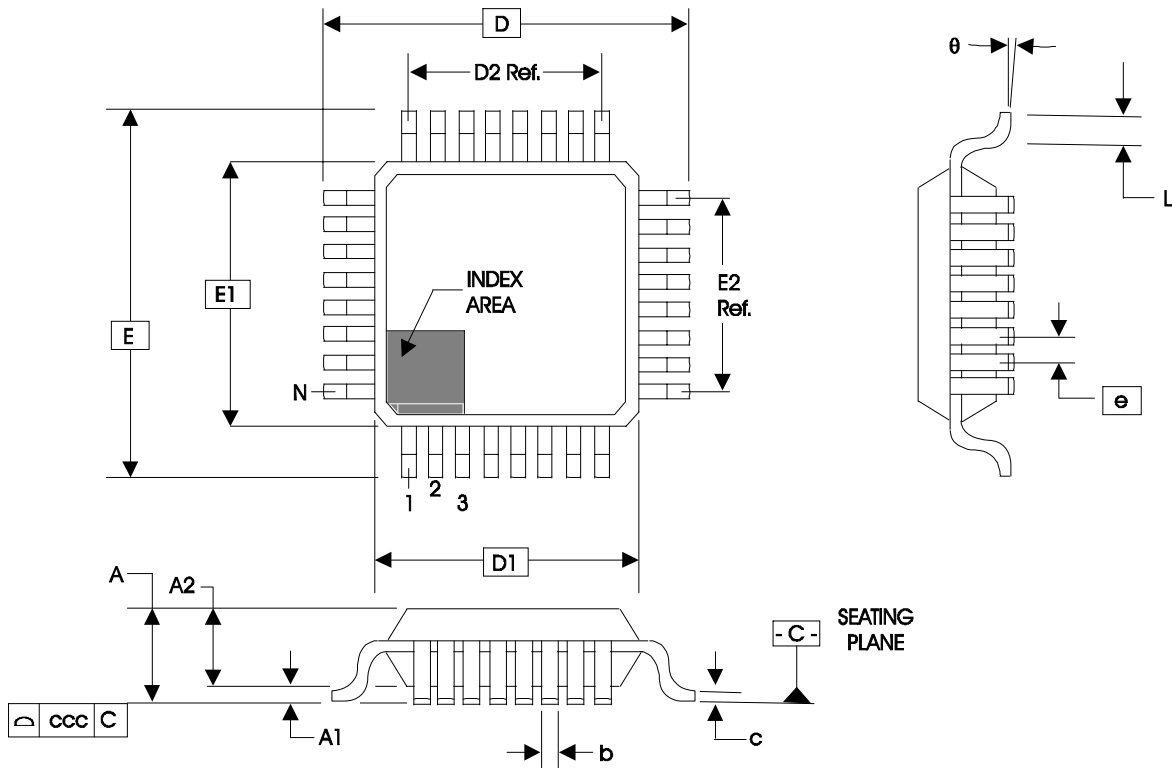


TABLE 7. PACKAGE DIMENSIONS

JEDEC VARIATION ALL DIMENSIONS IN MILLIMETERS			
SYMBOL	BBC		
	MINIMUM	NOMINAL	MAXIMUM
N	48		
A	--	--	1.60
A1	0.05	--	0.15
A2	1.35	1.40	1.45
b	0.17	0.22	0.27
c	0.09	--	0.20
D	9.00 BASIC		
D1	7.00 BASIC		
D2	5.50 Ref.		
E	9.00 BASIC		
E1	7.00 BASIC		
E2	5.50 Ref.		
e	0.50 BASIC		
L	0.45	0.60	0.75
theta	0°	--	7°
ccc	--	--	0.08

Reference Document: JEDEC Publication 95, MS-026

TABLE 8. ORDERING INFORMATION

Part/Order Number	Marking	Package	Shipping Packaging	Temperature
8344AY-01	ICS8344AY-01	48 Lead LQFP	tray	0°C to 70°C
8344AY-01T	ICS8344AY-01	48 Lead LQFP	1000 tape & reel	0°C to 70°C
8344AY-01LF	ICS8344AY0IL	48 lead "Lead-Free" LQFP	tray	0°C to 70°C
8344AY-01LFT	ICS8344AY0IL	48 lead "Lead-Free" LQFP	1000 tape & reel	0°C to 70°C

NOTE: Parts that are ordered with an "LF" suffix to the part number are the Pb-Free configuration and are RoHS compliant.

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REVISION HISTORY SHEET

Rev	Table	Page	Description of Change	Date
B	4A	4	Revised I_{DD} row from 60mA Max. to 95mA Max.	8/6/01
	4D	5	Revised I_{DD} row from 60mA Max. to 95mA Max.	
	4G	6	Revised I_{DD} row from 60mA Max. to 95mA Max.	
B	5A	7	Revised Note 1 and Note 4.	12/13/01
		8-10	Updated Parameter Measurement Figures. Deleted Power Consideration notes.	
B		1	Updated Block Diagram.	12/18/01
B	8	14	On April 18, 2001 a typo was corrected in the Ordering Information Table. The correction was ICS8344AY-01 from ICS8344BY-01.	7/24/02
B		1	Features Section - added lead-free bullet.	10/26/06
		10	Added <i>Recommendations for Unused Input and Output Pins</i> .	
		11	Added <i>Differential Clock Input Interface</i> .	
		14	Ordering Information Table - added lead-free part number, marking and note. Updated datasheet format.	
B	3A	3	Output Enable Function Table - updated table.	5/10/07
C	T3A - T3C	1	Added <i>Pullup</i> and <i>Pulldown</i> to Block Diagram.	9/8/08
		1	Features Section - added Additive Phase Jitter bullet.	
		2	Pin Characteristics Table - add C_{PD} specs.	
		3	Function Tables - added <i>default</i> to conditions.	
		7	AC Characteristics Table - added Additive Phase Jitter row.	
		8	Added Additive Phase Jitter Plot.	
8	15	Ordering Information Table - removed ICS prefix from part/order number column.		
C	T2	2	In C_{IN} row, replaced CLK-SEL with CLK_SEL.	9/9/08

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